

IFW



Docket No.: 05465.1440

PATENT/OFFICIAL

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :
David G. Ellsworth, et al. :
Serial No. 10/801,000 : Group Art Unit: 3682
Filed: March 16, 2004 : Examiner:
For: TENSION MEASUREMENT SYSTEM AND METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

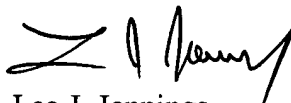
No further elaboration is believed necessary. Copies of the documents are submitted herewith in accordance with 37 C.F.R. §1.98(a).

AUTHORIZATION

This Information Disclosure Statement is being filed before receipt of the first Office Action. No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

Respectfully submitted,

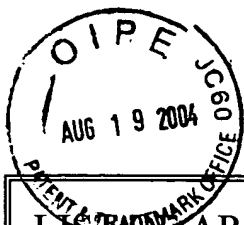
BAKER & HOSTETLER LLP



Leo J. Jennings
Registration No. 32,902

Date: August 19, 2004

Baker & Hostetler LLP
Washington Square, Suite 1100
1050 Connecticut Avenue, N.W.
Washington, D.C. 20036
Telephone: (202) 861 1500
Facsimile: (202) 861 1783



LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.
05165.1440

SERIAL NO.
10/801,000

APPLICANT
David G. Ellsworth, et al.

FILING DATE
3/16/04

GROUP
3682

U.S. PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A		5,167,159	12/1/92	willian M. Lucking	73	862.451	12/18/90
B		4,983,144	1/8/91	Juji Ojima	474	111	12/5/89
C		4,646,402	3/3/87	Franz-Josef Gierse, et al.	26	86	5/9/85
D		3,968,754	7/13/76	willy Lanfermann, et al.	104	172	1/13/75
E		3,728,896	4/24/73	Loren B. Sheldon, et al.	73	136	12/17/70
F							
G							
H							
I							
J							
K							
L							
M							
N							
O							
P							
Q							
R							
S							
T							

FOREIGN PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U							
V							
W							
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

HH	
II	
JJ	
KK	
LL	
MM	
NN	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.